



Test Report issued under the responsibility of:



TEST REPORT
IEC 60269-4
Low-voltage fuses
Part 4: Supplementary requirements for fuse-links for the protection of semiconductor devices

Report Number .....: 03601-A-24CB0184-S
Date of issue .....: 2024-12-05
Total number of pages..... 26



Name of Testing Laboratory preparing the Report.....: Suzhou Electrical Apparatus Science Research Institute Co., Ltd.(EETI)

Applicant's name.....: Zhejiang Tengen Electric Co., Ltd.

Address .....: Sulv Industry Zone, Liushi Town, Yueqing City, Zhejiang Province, P.R.China.

Test specification:

Standard.....: IEC 60269-4:2009, IEC 60269-4:2009/AMD1:2012, IEC 60269-4:2009/AMD2:2016
see also IEC 60269-1:2006, IEC 60269-1:2006/AMD1:2009, IEC 60269-1:2006/AMD2:2014

Test procedure .....: CB Scheme

Non-standard test method .....: N/A

TRF template used .....: IECEE OD-2020-F1:2022, Ed.1.5

Test Report Form No. ....: IEC60269\_4D

Test Report Form(s) Originator ....: CQC

Master TRF.....: Dated 2023-08-17

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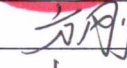
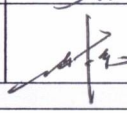
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<b>Test item description</b> .....	Fuse for protection of semiconductor devices	
<b>Trade Mark</b> .....	Tengen	
<b>Manufacturer</b> .....	Zhejiang Tengen Electric Co., Ltd. Sulv Industry Zone, Liushi Town, Yueqing City, Zhejiang Province, P.R.China.	
<b>Model/Type reference</b> .....	TGRS3Z-400BQ, TGRS3Z-400CQ	
<b>Ratings</b> .....	Un:DC250V/DC500V/DC750V/AC500V/AC690V/AC800V; In: 50A、 63A、 70A、 80A、 90A、 100A、 125A、 160A、 180A、 200A、 225A、 250A、 300A、 315A、 350A、 380A、 400A、 I1: 50kA(DC250V/DC500V/DC750V )/100kA(AC500V/AC690V/ AC800V);aR.	
<b>Responsible Testing Laboratory (as applicable), testing procedure and testing location(s):</b>		
<input checked="" type="checkbox"/> <b>CB Testing Laboratory:</b>	Suzhou Electrical Apparatus Science Research Institute Co., Ltd.(EETI)	
<b>Testing location/ address</b> .....	No.7 Yonghe Street, Binhe Road, New District, Suzhou, China	
<b>Tested by (name, function, signature).</b>	Fang Gang(Team leader)	
<b>Approved by (name, function, signature)</b> .....	Chen Yuan (Supervisor)	
<input type="checkbox"/> <b>Testing procedure: CTF Stage 1:</b>		
<b>Testing location/ address</b> .....		
<b>Tested by (name, function, signature).</b>		
<b>Approved by (name, function, signature)</b> .....		
<input type="checkbox"/> <b>Testing procedure: CTF Stage 2:</b>		
<b>Testing location/ address</b> .....		
<b>Tested by (name + signature).....</b>		
<b>Witnessed by (name, function, signature)</b> .....		
<b>Approved by (name, function, signature)</b> .....		
<input type="checkbox"/> <b>Testing procedure: CTF Stage 3:</b>		
<input type="checkbox"/> <b>Testing procedure: CTF Stage 4:</b>		
<b>Testing location/ address</b> .....		
<b>Tested by (name, function, signature).</b>		
<b>Witnessed by (name, function, signature)</b> .....		
<b>Approved by (name, function, signature)</b> .....		
<b>Supervised by (name, function, signature)</b> .....		